

## Growth and Characterization of SnSe Films for Photovoltaic Applications

조혜윤, 박진호<sup>†</sup>, 바수데바레디<sup>1</sup>  
영남대학교; <sup>1</sup>영남대학교 화학공학과  
(chperk@ynu.ac.kr<sup>†</sup>)

Tin monoselenide (SnSe) is considered one of the promising photovoltaic material due to its opto-electrical properties, earth-abundance, low-cost and low-toxicity compared to CdTe and PbTe. Thin films of SnSe have been successfully grown on corning glass substrates using chemical bath deposition (CBD). The as-prepared films were systematically characterized by XRD, Raman analysis and optical measurements. The XRD patterns for the films were recorded in  $2\theta$  range of  $20^\circ$ – $50^\circ$ , at a scan-rate of  $0.05^\circ$  using CuK $\alpha$  ( $\lambda = 0.154$  nm) radiation. All the reflection peaks in the diffraction pattern can be indexed to the orthorhombic crystal structure. The lattice parameters calculated to be  $a=1.1557$  nm,  $b=0.4127$  nm and  $c= 0.4429$  nm. Raman scattering analysis allowed the assignment of peaks at  $107$   $\text{cm}^{-1}$ ,  $130$   $\text{cm}^{-1}$  and  $151$   $\text{cm}^{-1}$  to the orthorhombic SnSe phase. The optical properties of the SnSe deposited were investigated by the UV-Vis-NIR reflectance and transmittance spectrum measured in the wavelength range of  $300 - 2500$  nm. The refractive index, extinction coefficient and energy band gap of the films was calculated. Hall-effect measurements showed p-type conductivity for all the SnSe films. The results will be presented and discussed.